

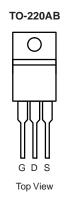
4N80L-TA3-T-VB Datasheet

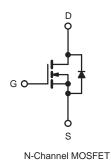
N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800			
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2		
Q _g (Max.) (nC)	200			
Q _{gs} (nC)	24			
Q _{gd} (nC)	110			
Configuration	Single			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D	5		
Continuous Drain Current		T _C = 100 °C		3.9	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation	T _C =	25 °C	PD	P _D 190		
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
			-	1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

RoHS

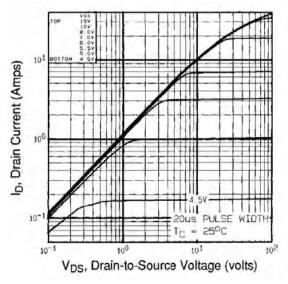


THERMAL RESISTANCE RATII	NGS							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 - - 0.65						
Case-to-Sink, Flat, Greased Surface	R _{thCS}				°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}							
SPECIFICATIONS ($T_J = 25 \text{ °C}$, u	nless otherwi	se noted)				1	1	1
PARAMETER	SYMBOL	TEST CONDITIONS		IONS	MIN.	TYP.	MAX.	UNIT
Static								
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 2	250 µA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	l _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 1	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20	V	-	-	± 100	nA
Zaura Oata Malta da Durán Ourrant		V _{DS} =	= 800 V, V _G	_{iS} = 0 V	-	-	100	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 640 \	/, V _{GS} = 0 \	/, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D	a = 3.7 A ^b	-	1.2	-	Ω
Forward Transconductance	g fs	V _{DS} =	100 V, I _D =	= 3.7 A ^b	5.6	-	-	S
Dynamic		1			<u> </u>	I	I	1
Input Capacitance	C _{iss}	N 0.V			-	3100	-	pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	800	-		
Reverse Transfer Capacitance	C _{rss}			-	490	-		
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$		-	-	24	nC	
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13 ^b		-	-	110	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A}, \\ \text{R}_{g} = 6.2 \ \Omega, \text{ R}_{D} = 52 \ \Omega \\ \text{see fig. 10^{b}}$		-	19	-	ns	
Rise Time	tr			-	38	-		
Turn-Off Delay Time	t _{d(off)}			-	120	-		
Fall Time	t _f			-	39	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-		
Internal Source Inductance	L _S			-	13	-	nH	
Drain-Source Body Diode Characteristic	S	<u>.</u>						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	•	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A	
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C, } I_{F} = 3.8 \text{ A,}$ dl/dt = 100 A/µs ^b		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn			-on is do			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



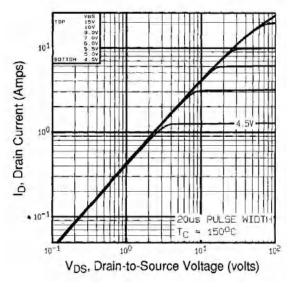


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

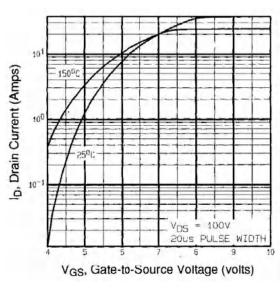
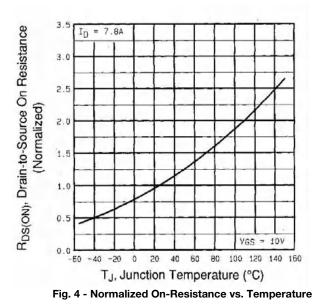


Fig. 3 - Typical Transfer Characteristics



4N80L-TA3-T-VB



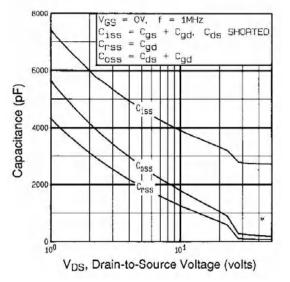


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 7 - Typical Source-Drain Diode Forward Voltage

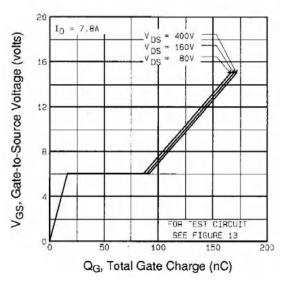
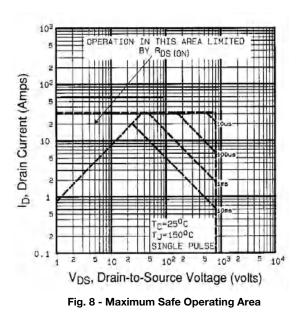


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





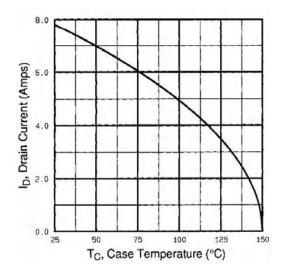


Fig. 9 - Maximum Drain Current vs. Case Temperature

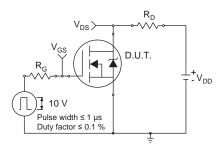


Fig. 10a - Switching Time Test Circuit



Fig. 10b - Switching Time Waveforms

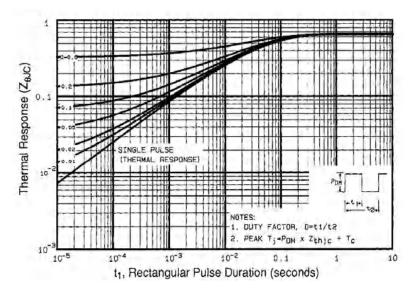


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



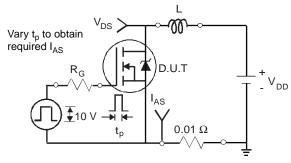


Fig. 12a - Unclamped Inductive Test Circuit

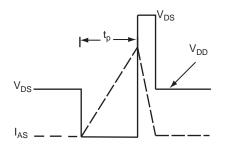


Fig. 12b - Unclamped Inductive Waveforms



Fig. 12c - Maximum Avalanche Energy vs. Drain Current

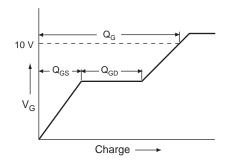


Fig. 13a - Basic Gate Charge Waveform

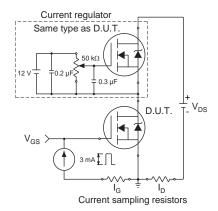
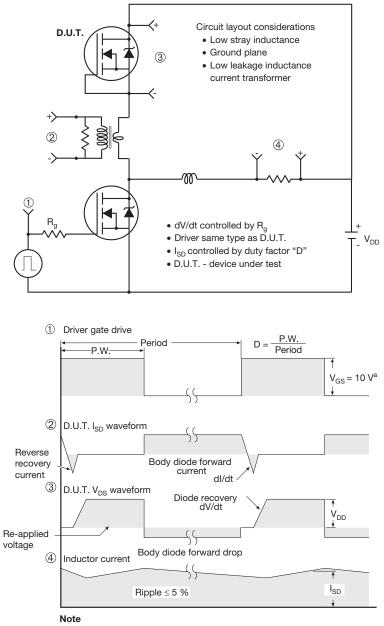


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

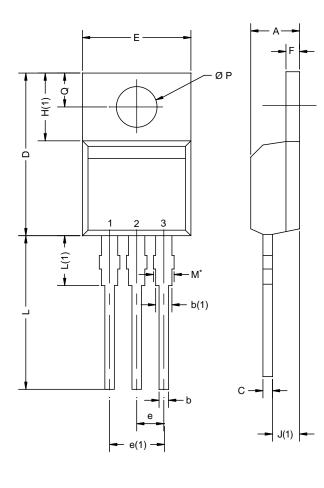


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
E	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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